

Search Notes

Application/Control No.

10/634,881

Examiner

LEE NGUYEN

Applicant(s)/Patent under
Reexamination

WILLEY ET AL.

Art Unit

SEARCHED

Class	Subclass	Date	Examiner
455	410 411	12/6/2006	LN
	41.2 41.3		
380	247 270		
713	168-172		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPG-PUB; USPAT; JPO; EPO; DERWENT) IEEE	12/6/2006	LN